Application/Control No.	Applicant(s)/Patent under Reexamination	
09/893,897	TOYAMA ET AL.	
Examiner	Art Unit	
Phu K. Nguyen	2628	

	<u> </u>		<u>. </u>	
	SEARCHED			
Class	Subclass	Date	Examiner	
345	419	7/10/2005	PN	
	422	7/10/2005	PN	
	426	7/10/2005	PN	
	600	7/10/2005	PN	
707	526	7/10/2005	PN	
358	357	7/10/2005	PN	
382	303	7/10/2005	PN	
Update	Search	12/27/2005	PN	
Update	search	5/29/2006	PN	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
345	419,426	5/29/2006	PN
707	526	5/29/2006	PN
358	357	5/29/2006	PN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST search SEE ATTACHED	7/10/2005	PN		
Nonpatent (IEEE, ACM) search SEE ATTACHED	7/10/2005	PN		
Inventor Name search SEE ATTACHED	7/10/2005	PN		
Update WEST, IEEE, ACM search	12/27/2005	PN		
Update WEST, IEEE, ACM search	5/29/2006	PN		